12.2-1   THE EFFECT OF CRYSTALLITE SIZE ON POWDER PATTERN RESOLUTION AND PHASE IDENTIFICA-TION -Deane K. Smith, The Pennsylvania State University University Park, Pennsylvania 16802, USA and Helein D. Bennett, National Aeronautics and Space Administration, John F. Kennedy Space Center, Florida 32899, USA

The inclusion of the crystallite size broaden-ing in the calculation of powder diffraction patterns illustrates the problem of peak resolution and its effect on phase identifica-tion using standard search procedures. Pat-terns of low resolution due to the method of recording the data or poor crystallinity are often difficult to match with patterns of high resolution, even for materials which are other-wise identical in all respects. This problem is common even with modern diffractometers when trying to identify corrosion products which are often poorly crystalline.

A program, SIMUL, has been prepared to use the d-I data sets of the Powder Diffraction File and simulate the diffractometer trace from which the data was originally extracted. A Cauchy or modified Cauchy profile is used with its alpha 1 peak corresponding to the I value. The envelope of all the peaks is used as the final trace. The initial calculation uses half widths corresponding to a highly crystalline sample on a well aligned diffractometer. A Gaussian profile whose half width corresponds to the Scherrer broadening for a specific crys-tallite size is convoluted with the calculated diffraction trace. The resulting trace can be compared with the experimental data obtained from a sample with crystallite size broadening.

The series of hydrated copper chlorides illus-trates the problems of identification when the pattern qualities are different. In this case there are several well defined reference pat-terns in the Powder Diffraction File. The well resolved pattern of $Cu_2Cl(OH)_3$, atacamite PDF-25-269, has its strongest three lines at 5.48A(100), 5.03(70) and 2.278(70). Using the broadening calculation for 200A crystallites, the three lines at 2.836(50), 2.779(50) and 2.759(55) coalesce and become the strongest line in the pattern. The other copper chlo-rides show similar effects. Whether using man-ual or computer searching, this identification would be a very difficult one to achieve.

SIMUL provides a means for the comparison of well- and poorly-resolved patterns. A cursory examination of patterns in the PDF show that many are modified significantly by broadening. The problem is most common when the pattern contains clusters of closely spaced lines of medium intensity. Similar calculations could be applied to comparing Debye-Scherrer and dif-fractometer data except that the problem is due to camera resolution in the case of the Debye-Scherrer camera.

12.2-2   A PROGRAM FOR COMPARING AND SELECTING OF X-RAY POWDER PATTERNS OF SUBSTANCES WITH SIMILAR STRUCTURES. By S.D.Kirik, S.A.Kovyazin, A.M.Fedotov, Institute of Chemistry and Chemi-cal Engineering, 42, K.Marx St.,Krasnoyarsk, 660049,U.S.S.R.; Computer Centre Siberian Bra-nch of USSR Academy of Sciences, Krasnoyarsk, 660036,U.S.S.R.

A computer program has been written for selec-tin X-ray powder patterns from automatic data base with a visual similarity to the certain pattern. Four criteria were tested as a quanti-tative measure of a visual similarity of pat-terns. Before comparison patterns are normali-sed. A powder pattern is considered as a dis-crete probability distribution of intensities. The distribution (pattern) is linearly trans-formed to a distribution with zero mathemati-cal expectation and unit variance. As a result of the normalisation correspondig elements of visually similar patterns become geometrically close. Two criteria are the area between dis-tribution functions and Levy's distance. The third criterion is a sum of distances between the nearest lines in compared normalized pat-terns, where the distances include difference of intensities. In the fourth criterion lines are compared succesively. The differnces in ra-tio of a distances between neighbouring lines and differences in ratio of line's intensities are summarized. The use of suggested criteria leads to the reasonable list of substances se-lected with the program. Structures of substan-ces can be considered as a constructive hypo-thesis to solve different problems of X-ray structure analysis.

12.2-3   NBS CRYSTAL DATA: COMPOUND IDENTIFICATION BY LATTICE MATCHING USING ELECTRON, X-RAY, OR NEUTRON DIFFRACTION DATA. By V.L. Himes and A.D. Mighell, Reactor Radiation Division, National Bureau of Standards, Gaithersburg, MD 20899.

The NBS Crystal Data Center maintains a database that contains evaluated crystallographic and chemical data on ~120,000 materials. The data fall into the following categories: metals, intermetallics, organometallics, minerals, inorganics and organics. As a source of critically evaluated data, the database can be used as a basis for scientific research or as an aid to research (e.g. to locate compounds with a given Pearson's code, to obtain bibliographic data, and to identify unknown compounds). Using lattice-formula matching techniques, unknown compounds can be identified against entries in NBS CRYSTAL DATA. The technique can be used once any cell defining the lattice has been determined. Cell parameters may be measured by electron, neutron, or x-ray diffraction using single-crystal or powder diffraction methods. Highlights of the method include: fast and highly automated; highly selective even when large tolerances are used for the cell parameters; identification possible in spite of typical errors made by experimentalists; excellent method for all classes of solid-state materials. NBS*SEARCH has been written to provide all the required software for lattice matching against NBS CRYSTAL DATA. The program is written in standard FORTRAN and is designed to be used in any analytical laboratory. The NBS*SEARCH software is multifunctional in design, and it is planned to incorporate additional search functions in forthcoming versions of this program. Both the software and the database are available from the JCPDS-International Centre for Diffraction Data.